



# HTD100N03-U

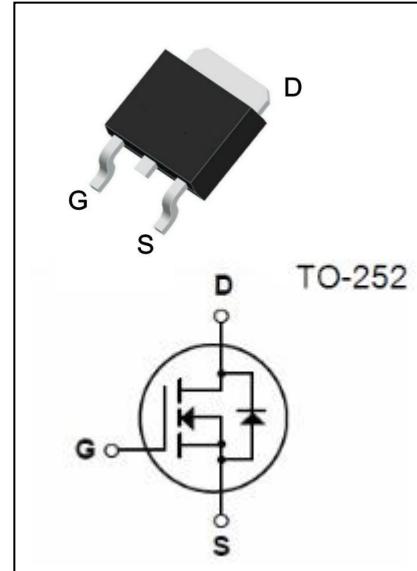
30V N-Channel MOSFET

## ● Features:

- 100A, 30V,  $R_{DS(on)(Typ)} = 3.3m\Omega$  @  $V_{GS} = 10V$
- Low Gate Charge
- Low  $C_{rss}$
- 100% Avalanche Tested
- Fast Switching
- Improved dv/dt Capability

## ● Application:

- High Frequency Switching Mode Power Supply
- Active Power Factor Correction



## Absolute Maximum Ratings( $T_c=25^\circ C$ unless otherwise noted)

| Symbol    | Parameter  | Value       | Unit          |
|-----------|--|-------------|---------------|
| $V_{DSS}$ | Drain-Source Voltage   | 30          | V             |
| $I_D$     | Drain Current - Continuous( $T_c=25^\circ C$ , Silicon limit)          | 100         | A             |
|           | Drain Current - Continuous( $T_c=25^\circ C$ , Package limit)          | 80          | A             |
|           | Drain Current - Continuous( $T_c=100^\circ C$ , Silicon limit)         | 63.2        | A             |
| $I_{DM}$  | Drain Current -Pulsed  | 240*        | A             |
| $V_{GSS}$ | Gate-Source Voltage  | $\pm 20$    | V             |
| $E_{AS}$  | Single Pulsed Avalanche Energy<br>( Limit Reference Value )<br>(Note5) | 119         | mJ            |
| $P_D$     | Power Dissipation( $T_c = 25^\circ C$ )<br>-Derate above $25^\circ C$  | 58          | W             |
|           |  | 0.46        | W/ $^\circ C$ |
| $T_j$     | Operating Junction Temperature   | 150         | $^\circ C$    |
| $T_{stg}$ | Storage Temperature Range  | -55 to +150 | $^\circ C$    |

## Thermal Characteristics

| Symbol          | Parameter                                   | Max  | Unit           |
|-----------------|---|------|----------------|
| $R_{\theta JC}$ | Thermal Resistance,Junction to Case (Note2) | 2.16 | $^\circ C / W$ |

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**Electrical Characteristics(Tc=25°C unless otherwise noted)**

| Symbol  | Parameter  | Test Conditons  | Min | Typ  | Max  | Unit |
|---|--|---|-----|------|------|------|
| <b>Off Characteristics</b>                                    |  |   |     |      |      |      |
| BV <sub>DSS</sub>   | Drain-source Breakdown Voltage                                   | V <sub>GS</sub> =0V ,I <sub>D</sub> =250μA  | 30  | --   | --   | V    |
| I <sub>DSS</sub>  | Zero Gate Voltage Drain Current                                  | V <sub>DS</sub> =30V,V <sub>GS</sub> =0V  | --  | --   | 1    | μA   |
| I <sub>GSSF</sub>   | Gate-Body Leakage Current,Forward                                | V <sub>GS</sub> =+20V, V <sub>DS</sub> =0V  | --  | --   | 100  | nA   |
| I <sub>GSSR</sub>   | Gate-Body Leakage Current,Reverse                                | V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V  | --  | --   | -100 | nA   |
| <b>On Characteristics</b> (Note3)                             |  |   |     |      |      |      |
| V <sub>GS(th)</sub>   | Gate Threshold Voltage   | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA                                   | 1.0 | 1.6  | 2.5  | V    |
| R <sub>DS(on)</sub>   | Static Drain-Source On-Resistance                                | V <sub>GS</sub> =10 V, I <sub>D</sub> =40A  | --  | 3.3  | 4.5  | mΩ   |
| R <sub>DS(on)</sub>   | Static Drain-Source On-Resistance                                | V <sub>GS</sub> =4.5 V, I <sub>D</sub> =40A   | --  | 5.5  | 7.5  | mΩ   |
| <b>Dynamic Characteristics</b> (Note4)                        |  |   |     |      |      |      |
| C <sub>iss</sub>  | Input Capacitance  | V <sub>DS</sub> =15V, V <sub>GS</sub> =0V,<br>f=1.0MHz                                      | --  | 3130 | --   | pF   |
| C <sub>oss</sub>  | Output Capacitance   |   | --  | 353  | --   | pF   |
| C <sub>rss</sub>  | Reverse Transfer Capacitance                                     |   | --  | 305  | --   | pF   |
| <b>Switching Characteristics</b> (Note4)                      |  |   |     |      |      |      |
| t <sub>d(on)</sub>  | Turn-On Delay Time   | V <sub>DD</sub> = 15 V, I <sub>D</sub> =20 A,<br>R <sub>G</sub> =2.5Ω, V <sub>GS</sub> =10V | --  | 13.5 | --   | ns   |
| t <sub>r</sub>  | Turn-On Rise Time  |   | --  | 18   | --   | ns   |
| t <sub>d(off)</sub>   | Turn-Off Delay Time  |   | --  | 59   | --   | ns   |
| t <sub>f</sub>  | Turn-Off Fall Time   |   | --  | 17   | --   | ns   |
| Q <sub>g</sub>  | Total Gate Charge  | V <sub>DS</sub> =15 V, I <sub>D</sub> =20A,<br>V <sub>GS</sub> = 10 V                       | --  | 51   | --   | nC   |
| Q <sub>gs</sub>   | Gate-Source Charge   |   | --  | 12   | --   | nC   |
| Q <sub>gd</sub>   | Gate-Drain Charge  |   | --  | 11   | --   | nC   |
| <b>Drain-Source Diode Characteristics and Maximum Ratings</b> |  |   |     |      |      |      |
| I <sub>S</sub>  | Maximum Continuous Drain-Source Diode Forward Current<br>(Note2) |   | --  | --   | 100  | A    |
| I <sub>SM</sub>   | Maximum Pulsed Drain-Source Diode Forward Current                |   | --  | --   | 240  | A    |
| V <sub>SD</sub>   | Drain-Source Diode Forward Voltage                               | V <sub>GS</sub> =0V,I <sub>S</sub> =40A (Note3)   | --  | --   | 1.4  | V    |
| t <sub>rr</sub>   | Reverse Recovery Time  | V <sub>GS</sub> =0V, I <sub>S</sub> =20A,<br>d I <sub>F</sub> /dt=100A/μs (Note3)           | --  | 42   | --   | ns   |
| Q <sub>rr</sub>   | Reverse Recovery Charge  |   | --  | 33   | --   | nC   |

## Notes:

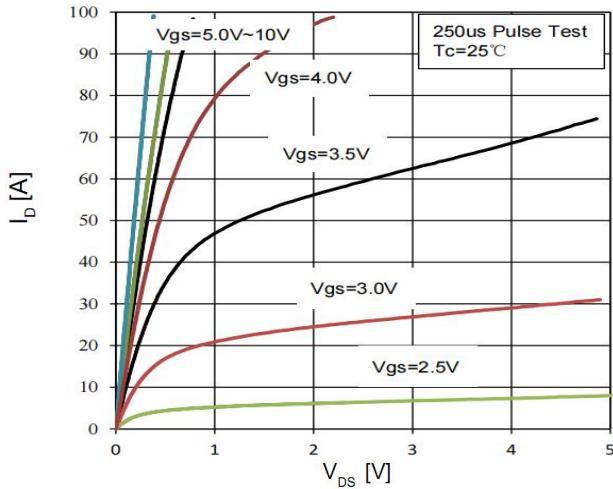
1. Repetitive Rating:Pulse Width Limited by Maximum Junction Temperature.
2. Surface Mounted on FR4 Board, t ≤ 10 sec.
3. Pulse Test : Pulse Width ≤300 μ s, Duty Cycle≤2%.
4. Guaranteed by design, not subject to production.
5. EAS condition: L = 0.5mH, I<sub>AS</sub> =17A, V<sub>DD</sub> = 20V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C.



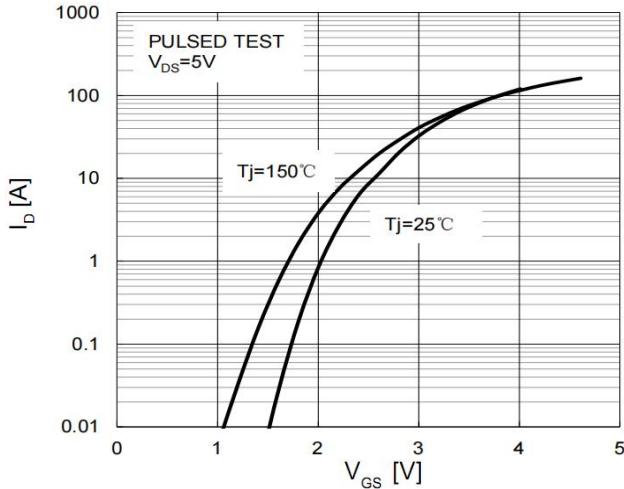
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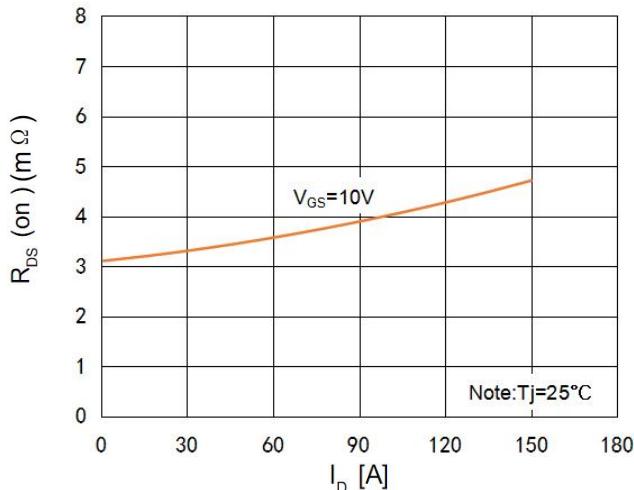
### On-Region Characteristics



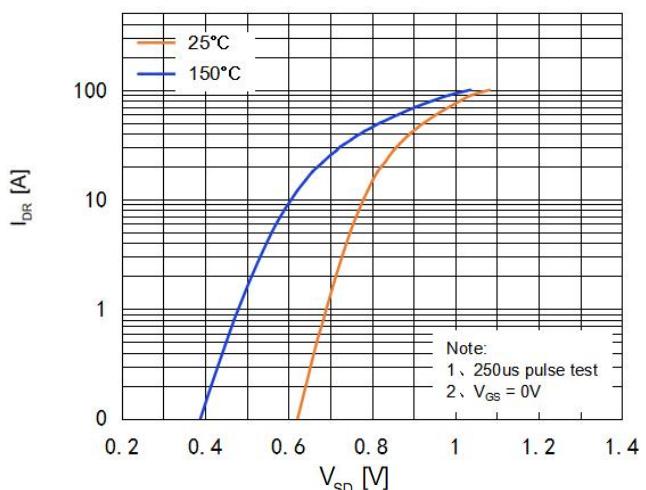
### Transfer Characteristics



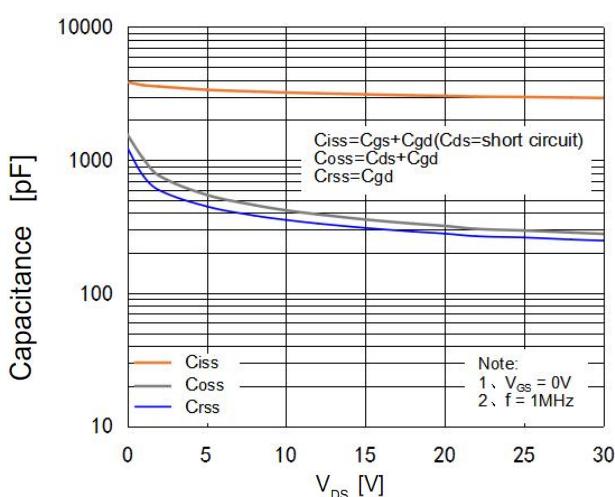
### On-Resistance Variation vs. Drain Current and Gate Voltage



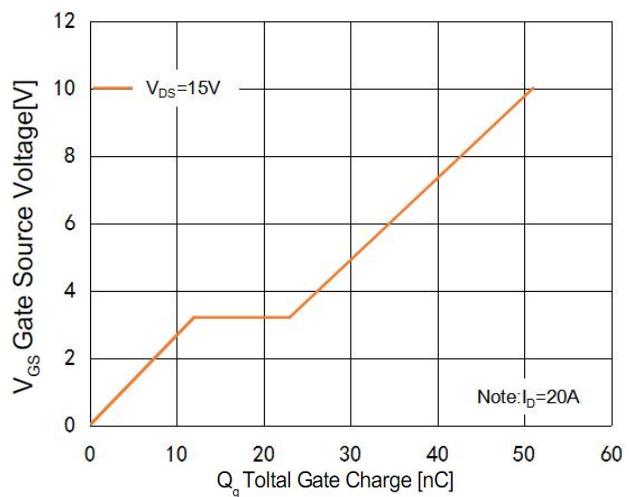
### Body Diode Forward Voltage Variation vs. Source Current and Temperature



### Capacitance Characteristics

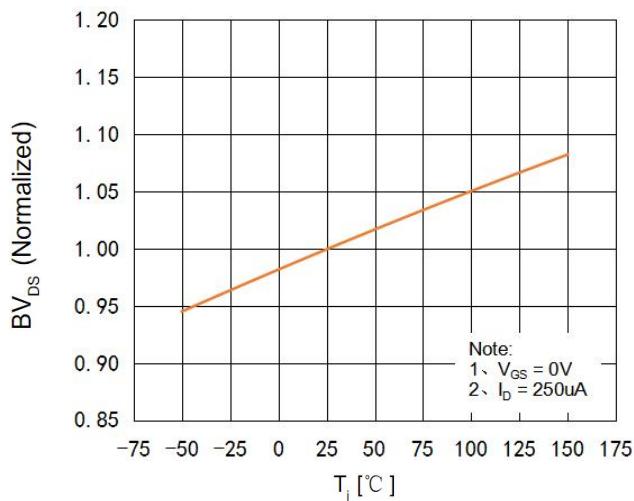
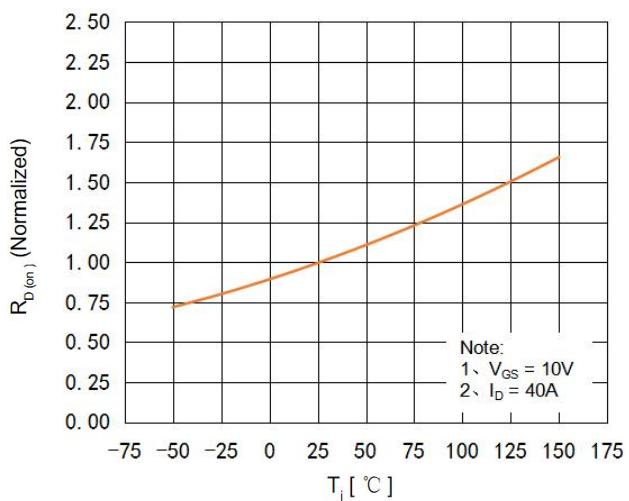
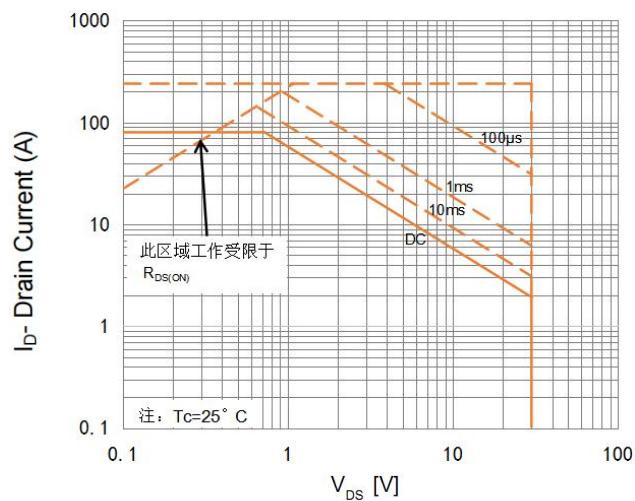
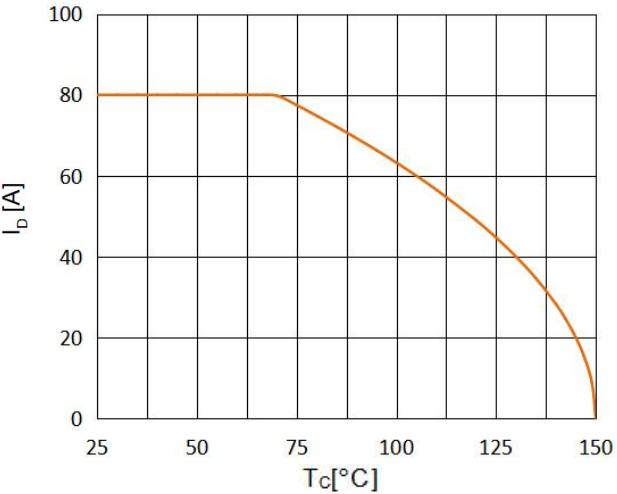


### Gate Charge Characteristics



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**Breakdown Voltage Variation  
vs. Temperature****On-Resistance Variation  
vs. Temperature****Maximum Safe Operating Area****Maximum Drain Current  
Vs. Case Temperature**



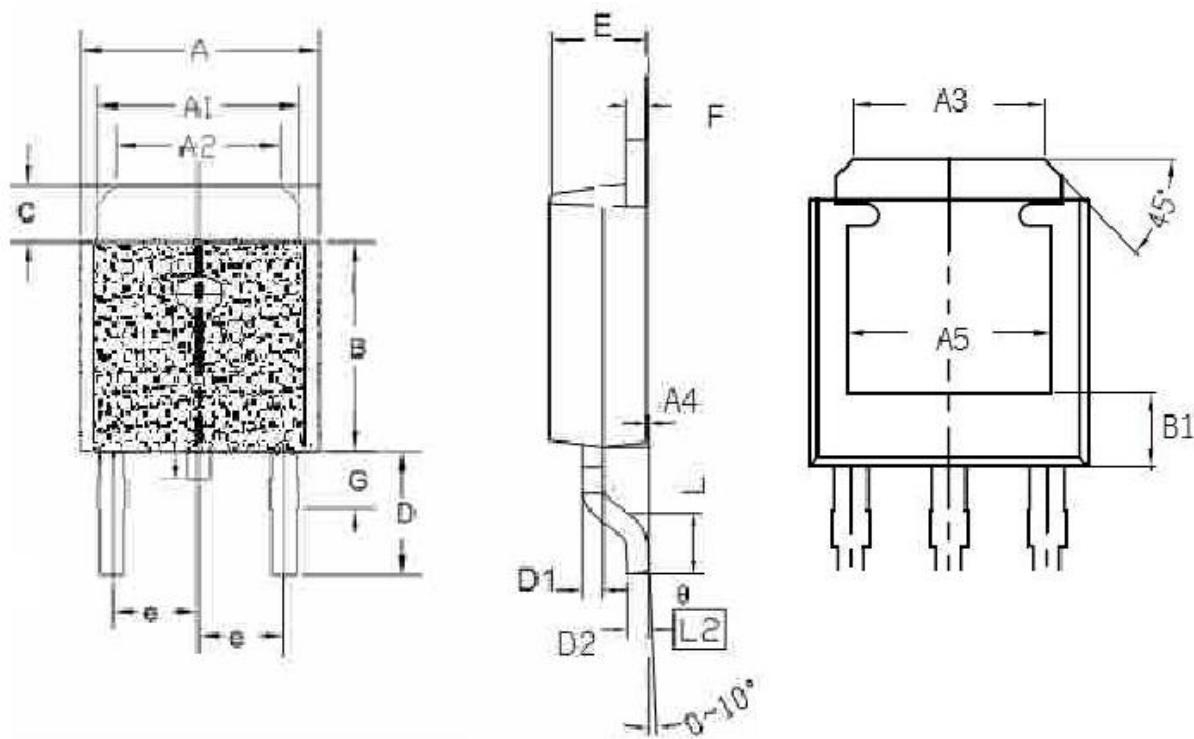
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### TO-252 Package Dimensions

UNIT: mm

| SYMBOL | min  | nom | max  | SYMBOL | min  | nom  | max   |
|--------|------|-----|------|--------|------|------|-------|
| A      | 6.40 |     | 6.60 | D      | 2.90 |      | 3.10  |
| A1     | 5.20 |     | 5.40 | D1     | 0.45 |      | 0.55  |
| A2     | 4.40 |     | 4.60 | D2     | 0.45 |      | 0.55  |
| A3     | 4.40 |     | 4.60 | e      |      | 2.30 |       |
| A4     | 0    |     | 0.15 | E      | 2.20 |      | 2.40  |
| A5     | 4.65 |     | 4.95 | F      | 0.45 |      | 0.55  |
| B      | 5.90 |     | 6.20 | G      |      | 1.70 |       |
| B1     | 1.57 |     | 1.77 | L      | 1.40 |      | 1.60  |
| C      | 0.90 |     | 0.96 | θ (度)  | 0    |      | 10.00 |





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注意事项：

- 1、在电路设计时请不要超过器件的最大额定值，否则会影响整机的可靠性。
- 2、MOSFET产品为静电敏感型器件，使用时应注意采取防静电保护措施，如佩戴防静电手环、设备接地等。
- 3、如需安装散热片，请注意控制扭力大小及散热片的平整度。
- 4、该规格书由华科公司制作，并可能不定期更改，恕不另行通知。
- 5、如有疑问，请及时联系我司销售代表。

版本履历表：

| 序号 | 版本号  | 修改时间      | 修改记录 |
|----|------|-----------|------|
| 1  | V1.0 | 2023-9-20 | 首次发行 |
|    |      |           |      |